

Notice of References Cited	Application/Control No. 09/784,550	Applicant(s)/Patent Under Reexamination ERICSON ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,804,949	02-1989	Faulkerson, James L.	345/166
	B	US-6,259,449 B1	07-2001	Saxena et al.	345/853
	C	US-5,574,804	11-1996	Olschafskie et al.	382/313
	D	US-6,269,336 B1	07-2001	Ladd et al.	704/270
	E	US-4,588,282	05-1986	Levine, Alfred B.	358/473
	F	US-5,870,723	02-1999	Pare et al.	705/39
	G	US-6,040,829	03-2000	Croy et al.	345/864
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,128,007	10-2000	Seybold, John L.	345/179
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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